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J. Steptun
8-1-03IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: LUKAS HOWALD ET AL. Docket No.: 01-352
Serial No.: 09/873,664 Examiner : B. Mouttet
Filed : June 4, 2001 Art Unit : 2853
For : SCANNING TIP AND PROCESS FOR ITS
PRODUCTION AND USE, PARTICULARLY
FOR A SCANNING PROBE MICROSCOPE

900 Chapel Street
Suite 1201
New Haven, CT 06510-2802

AMENDMENT UNDER 37 C.F.R. 1.111

Mail Stop Non-Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In response to U.S. Patent and Trademark Office Action
mailed April 23, 2003, please amend as follows:

IN THE SPECIFICATION:

Please replace the paragraph beginning at page 11, line 7, with
the following rewritten paragraph:

In the next step, the cantilever or the component onto which the
tip should be mounted is prepared. In Fig. 1a this cantilever is
called a "tuning fork". In the example shown and described, a
corresponding semiconductor wafer is cleaned using $H_2SO_4 + H_2O_2$ in
order to remove any organic material from the surface.

Preferably, the provided primer is used for the photosensitive
resist material, here EPON SU-8 (e.g., from the companies Micro
Resist Technology or SOTEC), since gold is not affected or

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